

Product Report



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Product: Ni sub-micro particles DTI-Ni-LB4M031

Batch: DTI-Ni-LB4M031

Description: Nickel sub-micro particles

Tests: PXRD, SEM

Storage: Store material at room temperature and avoid direct light exposure. After use,

dispose of remaining materials at local waste handling facility. Do NOT release

material to aqueous environments.

Conditions: The work has been performed according to the general terms and conditions of The

Danish Technological Institute. The test results are solely referring to the tested

(examined) materials.

Publication of extracts from the product report is allowed, if the testing laboratory

has given a written approval.

Place: Danish Technological Institute, Taastrup,

Nano Production and Micro Analysis

Signature: Zachary J. Davis

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Tests



- A X-ray diffractometer (XRD) equipped with a Cu X-ray source (K_{α} wavelength 1.5406 Å). This instrument allows the crystalline phases in the powder samples to be analyzed (identification and relative quantification of phases).
- Scanning electron microscope (SEM) equipped with X-ray microanalysis facilities (EDX). This allows microstructure and element composition to be analyzed.

Test results

Table: average results

BATCH NAME	DTI-NI-LB4M031
SEM SIZES	300 nm
PXRD AVERAGE CRYSTALLITE SIZES	30 nm

Documentation

Figure: SEM

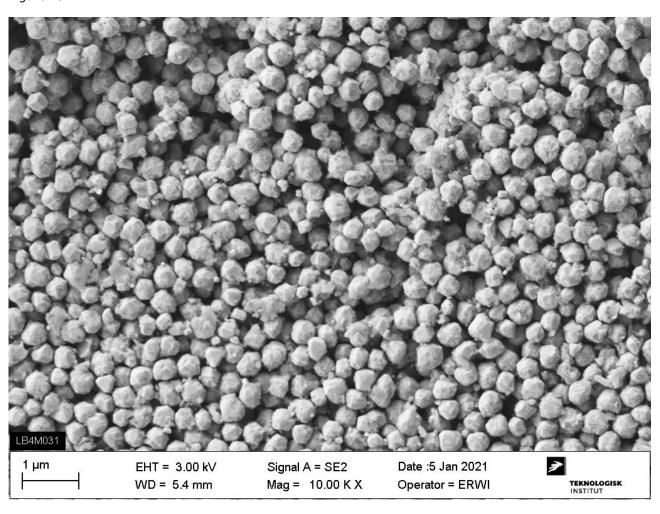




Figure: PXRD

